

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/718,304	YOO ET AL.
Examiner	Art Unit	
Suk Jin Kang	2619	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (see attached search strategy)	7/16/2007	SJK
Inventor name and Assignee search in PALM ExPO and EAST	7/16/2007	SJK
Consulted with Chau Nguyen (SPE)	7/16/2007	SJK
Updated Search (see attached search strategy)	1/7/2008	SJK
IEEE Xplore Database	1/7/2008	SJK
Consulted with George Bugg (PE)	1/10/2008	SJK
Consulted with Reinhard Eisenzopf (QAS)	1/10/2008	SJK
Consulted with Chau Nguyen (SPE)	1/14/2008	SJK